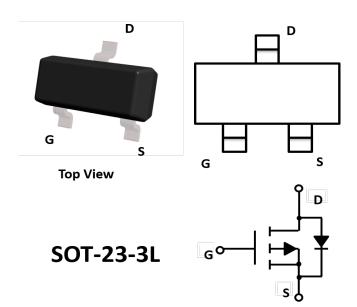


YJL07P03AL



P-Channel Enhancement Mode Field Effect Transistor



Product Summary

V_{DS} -30V
 I_D -7.0A
 R_{DS(ON)}(at V_{GS}=-10V) <25mohm

<36mohm

• R_{DS(ON)}(at V_{GS}=-4.5V)

- General Description
 Trench Power LV MOSFET technology
- High density cell design for Low R_{DS(ON)}
- High Speed switching

Applications

- Battery protection
- Load switch
- Power management

■ Absolute Maximum Ratings (T_A=25°C unless otherwise noted)

	Parameter	Symbol	Maximum	Unit	
Drain-source Voltage		V_{DS}	-30	V	
Gate-source Voltage		V_GS	±20	V	
Drain Current	T _A =25℃ @ Steady State	I _D	-7.0	А	
Drain Current	T _A =70℃ @ Steady State	ID	±20 -7.0		
Pulsed Drain Current ^A		I _{DM}	-50	Α	
Total Power Dissipation @ 1	Total Power Dissipation @ T _A =25℃		1.9	W	
Thermal Resistance Junctio	n-to-Ambient @ Steady State ^B	R _{eJA}	65.7	°C/W	
Junction and Storage Tempo	ge Temperature Range T _J ,T _{STG}		-55~+150	$^{\circ}$	

■ Ordering Information (Example)

PR	REFERED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
Y	JL07P03AL	F2	3007.	3000	30000	120000	7" reel



YJL07P03AL

■ Electrical Characteristics (T_J=25°C unless otherwise noted)

Parameter Symbol Condition		Conditions	Min	Тур	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D =-250μA	-30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-30V,V _{GS} =0V,T _C =25°C			-1	μΑ
Gate-Body Leakage Current	I _{GSS}	V_{GS} = $\pm 20V$, V_{DS} = $0V$			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D =-250μA	-1.0	-1.5	-2.5	V
Otatis Paris Oceano On Paristance		V _{GS} = -10V, I _D =-7.0A		18.5	25	mΩ
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} = -4.5V, I _D =-5.0A		24.5	36	
Diode Forward Voltage	V _{SD}	I _S =-7.0A,V _{GS} =0V		-0.8	-1.2	V
Maximum Body-Diode Continuous Current	Is				-7.0	А
Dynamic Parameters						
Input Capacitance	C _{iss}			1500		pF
Output Capacitance	Coss	V _{DS} =-15V,V _{GS} =0V,f=1MHZ		178		
Reverse Transfer Capacitance	C _{rss}			146		
Switching Parameters						
Total Gate Charge	Qg			28.7		nC
Gate Source Charge	Q_{gs}	V _{GS} =-10V,V _{DS} =-15V,I _D =-6.0A		5.5		
Gate Drain Charge	Q_{gd}			5.4		
Reverse Recovery Charge	Q _{rr}	L - 04 didb-5004/v-		6.0		
Reverse Recovery Time	t _{rr}	I _F = -9A, di/dt=500A/us		14		
Turn-on Delay Time	t _{D(on)}			10		
Turn-on Rise Time	t _r	V _{GS} =-10V,V _{DS} =-15V, I _D =-6.0A,		44		ns
Turn-off Delay Time	$t_{D(off)}$	R _{GEN} =2.5Ω		54		
Turn-off Fall Time	t _f			59		

A. Pulse Test: Pulse Width \leqslant 300us, Duty cycle \leqslant 2%.

B. $R_{\theta JA}$ is the sum of the junction-to-lead and lead-to-ambient thermal resistance, where the lead thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JA}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.



■ Typical Performance Characteristics

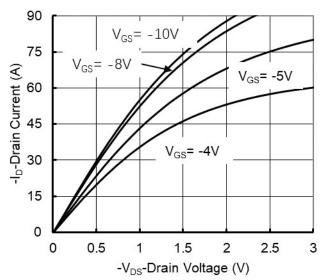


Figure 1. Output Characteristics

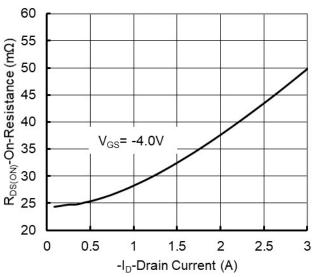


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

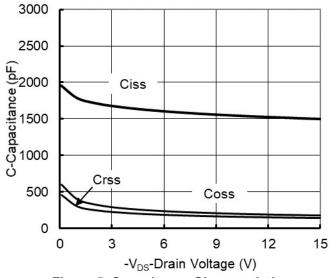


Figure 5. Capacitance Characteristics

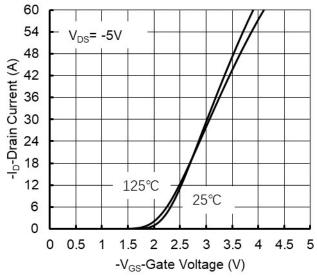


Figure 2. Transfer Characteristics

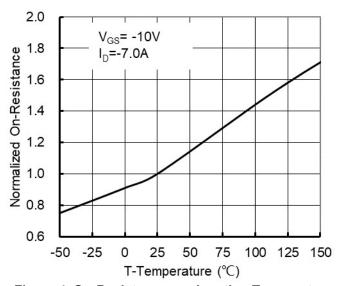


Figure 4. On-Resistance vs. Junction Temperature

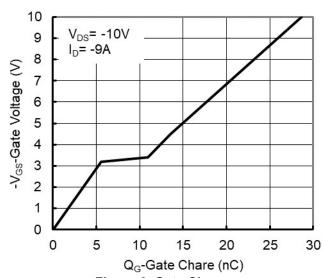
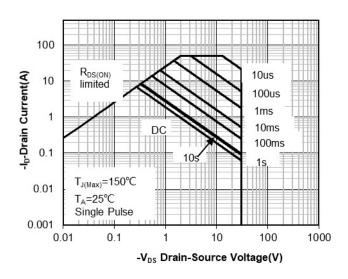


Figure 6. Gate Charge







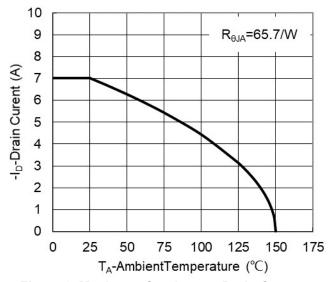


Figure 7. Safe Operation Area

Figure 8. Maximum Continuous Drain Current vs Ambient Temperature

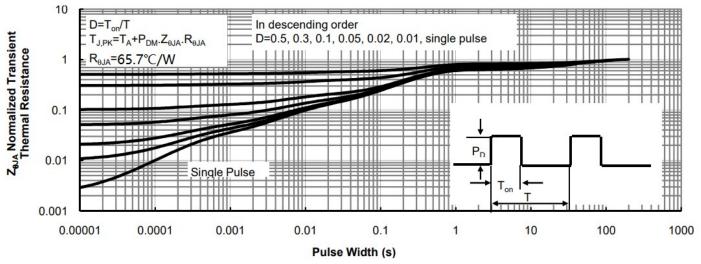
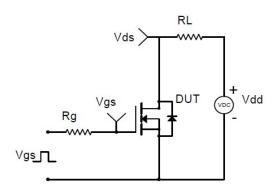
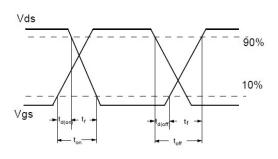


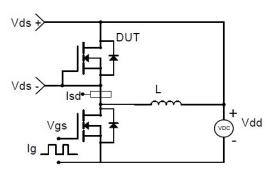
Figure 9. Normalized Maximum Transient Thermal Impedance

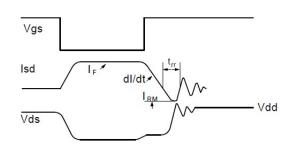




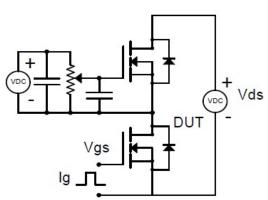


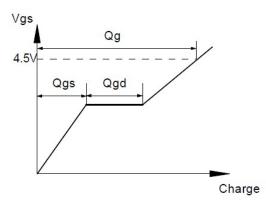
Resistive Switching Test Circuit & Waveforms



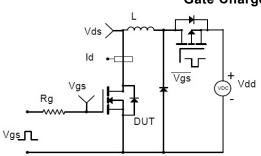


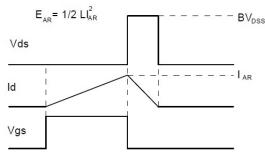
Diode Recovery Test Circuit & Waveforms





Gate Charge Test Circuit & Waveform





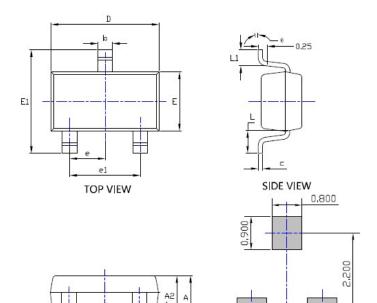
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





SIDE VIEW

■ SOP-23-3L Package information



SUGGESTED SOLDER PAD LAYOUT

0.950

UNIT: mm

0.950

	92	0.000 Pers	DIMENS	SIDNS			
SYMBOL	INCHES			Millimeter			
	MIN.	NDM,	MAX.	MIN.	NDM,	MAX.	
Α	0.041		0.049	1.050		1.250	
A1	0.000		0.008	0.000		0.200	
A2	0.041	0.043	0.045	1,050	1.100	1,150	
lo	0.012	0.016	0.020	0.300	0.400	0.500	
C	0.004		0.008	0,100		0,200	
D	0.111	0,115	0.119	2,820	2.920	3.020	
Ε	0.059	0.063	0.067	1.500	1.600	1,700	
E1	0.104	0.110	0.116	2.650	5.800	2.950	
6	0.037TYP			0.950TYP			
e1	0.071	0.075	0.079	1.800	1.900	2.000	
L	0.024REF			0.600REF			
L1	0.012	0.018	0.240	0.300	0.450	0.600	
9	0.	C	8.	0*		8*	

- NOTE: 1,PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
- 2, TOLERANCE 0, 1mm UNLESS OTHERWISE SPECIFIED.
- 3.THE PAD LAYOUT IS FOR REFERENCE PURPOSES ONLY.



YJL07P03AL

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